SNx4AHCT126 Quadruple Bus Buffer Gates With 3-State Outputs

1 Features

- Inputs are TTL-voltage compatible
- Latch-up performance exceeds 250mA per JESD 17
- ESD protection exceeds JESD 22:
  - 2000V Human-Body Model (A114-A)
  - 200V Machine Model (A115-A)
- On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

2 Applications

- Servers
- PCs and notebooks
- Network switches
- Wearable health and fitness devices
- Telecom infrastructures
- Electronic points-of-sale

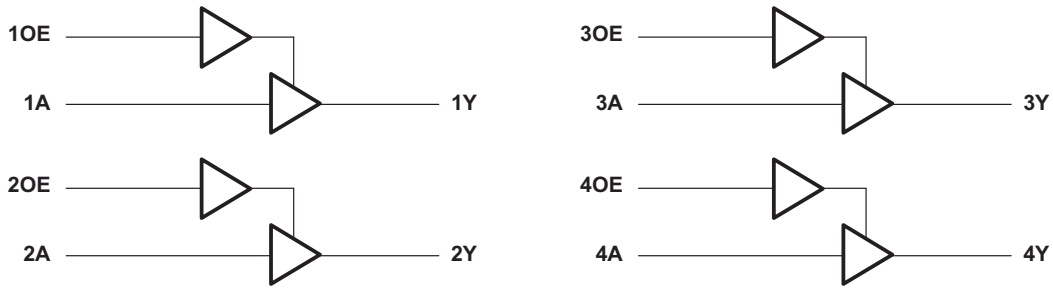
3 Description

The SNxAHCT126 devices are quadruple-bus buffer gates featuring independent line drivers with 3-state outputs.

Device Information

PART NUMBER	RATING	PACKAGE SIZE(1)
SN54AHCT126	Military	D (SOIC, 14)
		DB (SSOP, 14)
		DGV (TVSOP, 14)
SN74AHCT126	Commercial	NS (PDIP, 14)
		N (SOP, 14)
		PW (TSSOP, 14)
		J (CDIP, 14)
		W (CFP, 14)
		BQA (WQFN, 14)
		FK (LCCC, 20)

(1) For more information, see Section 11.



Simplified Schematic

An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.

Table of Contents

1 Features....1
2 Applications....1
3 Description....1
4 Pin Configuration and Functions....3
5 Specifications....5
5.1 Absolute Maximum Ratings....5
5.2 ESD Ratings....5
5.3 Recommended Operating Conditions....5
5.4 Thermal Information....6
5.5 Electrical Characteristics....6
5.6 Switching Characteristics, V_{CC} = 5 V ± 0.5 V....7
5.7 Noise Characteristics....7
5.8 Operating Characteristics....7
5.9 Typical Characteristics....8
6 Parameter Measurement Information....9
7 Detailed Description....10
7.1 Overview....10
7.2 Functional Block Diagram....10
7.3 Feature Description....10
7.4 Device Functional Modes....10
8 Application and Implementation....11
8.1 Application Information....11
8.2 Typical Application....11
8.3 Power Supply Recommendations....12
8.4 Layout....12
9 Device and Documentation Support....13
9.1 Receiving Notification of Documentation Updates....13
9.2 Support Resources....13
9.3 Trademarks....13
9.4 Electrostatic Discharge Caution....13
9.5 Glossary....13
10 Revision History....13
11 Mechanical, Packaging, and Orderable Information....13

Copyright © 2024 Texas Instruments Incorporated

4 Pin Configuration and Functions

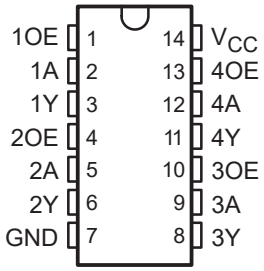
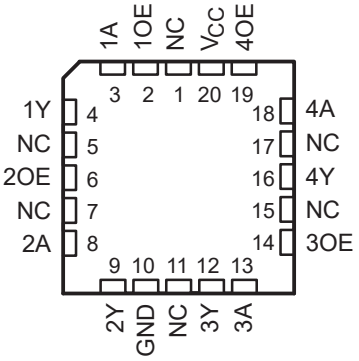


Figure 4-1. SN54AHCT126 J or W Packages, CDIP or CFP SN74AHCT126 D, DB, DGV, N, NS, or PW Packages, 14-Pin SOIC, SSOP, TVSOP, PDIP, SOP or TSSOP (Top View)



NC – No internal connection

Figure 4-2. SN54AHCT126 FK Package, 20-Pin LCCC (Top View)

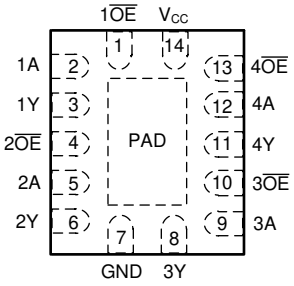


Figure 4-3. SNx4AHCT126 BQA Package, 14-Pin WQFN (Top View)

Table 4-1. Pin Functions

PIN				TYPE[1]	DESCRIPTION
NAME	SN74AHCT126	SN54AHCT126			
	D, DB, DGV, N, NS, PW, BQA	J, W	FK		
1A	2	2	3	I	1A Input
1OE	1	1	2	I	Output Enable 1
1Y	3	3	4	O	1Y Output
2A	5	5	8	I	2A Input
2OE	4	4	6	I	Output Enable 2
2Y	6	6	9	O	2Y Output
3A	9	9	13	I	3A Input
3OE	10	10	14	I	Output Enable 3
3Y	8	8	12	O	3Y Output
4A	12	12	18	I	4A Input
4OE	13	13	19	I	Output Enable 4
4Y	11	11	16	O	4Y Output
GND	7	7	10	—	Ground Pin

Copyright © 2024 Texas Instruments Incorporated

Table 4-1. Pin Functions (continued)

PIN				TYPE[1]	DESCRIPTION
NAME	SN74AHCT126	SN54AHCT126			
	D, DB, DGV, N, NS, PW, BQA	J, W	FK		
NC		—	1	—	No Connection
			5		
			7		
			11		
			15		
			17		
V_{CC}	14	14	20	—	Power Pin
Thermal Pad[2]				—	Thermal Pad

(1) I = input, O = output
(2) For BQA package only

Copyright © 2024 Texas Instruments Incorporated

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V_{CC}	Supply voltage range		–0.5	7	V
V_I	Input voltage range(2)		–0.5	7	V
V_O	Output voltage range(2)		–0.5	V_{CC} + 0.5	V
I_{IK}	Input clamp current	V_I < 0		–20	mA
I_{OK}	Output clamp current	V_O < 0 or V_O > V_{CC}		±20	mA
I_O	Continuous output current	V_O = 0 to V_{CC}		±25	mA
	Continuous current through V_{CC} or GND			±50	mA

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

5.2 ESD Ratings

			MIN	MAX	UNIT
T_{stg}	Storage temperature range		–65	150	°C
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins(1)	0	2000	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(2)

		SN54AHCT126(1)		SN74AHCT126		UNIT
		MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage	4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage	2		2		V
V_{IL}	Low-level input voltage		0.8		0.8	V
V_I	Input voltage	0	5.5	0	5.5	V
V_O	Output voltage	0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current		–8		–8	mA
I_{OL}	Low-level output current		8		8	mA
Δt/Δv	Input transition rise or fall rate		20		20	ns/V
T_A	Operating free-air temperature	–55	125	–40	125	°C

(1) Product Preview.
(2) All unused inputs of the device must be held at V_{CC} or GND for proper device operation. Refer to the TI Application Report, *Implications of Slow or Floating CMOS Inputs* (SCBA004).

Copyright © 2024 Texas Instruments Incorporated

5.4 Thermal Information

THERMAL METRIC[1]		SN74AHCT126							UNIT
		D	DB	DGV	N	NS	PW	BQA	
		14 PINS							
$R_{\theta JA}$	Junction-to-ambient thermal resistance	124.5	107.1	129.0	57.4	120.9	147.7	88.3	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	78.8	59.6	52.1	44.9	78.2	77.4	90.9	
$R_{\theta JB}$	Junction-to-board thermal resistance	81	54.4	62.0	37.2	81.6	90.9	56.8	
ψ_{JT}	Junction-to-top characterization parameter	37	20.5	6.5	30.1	42.8	27.2	9.9	
ψ_{JB}	Junction-to-board characterization parameter	80.6	53.8	61.3	37.1	81.1	90.2	56.7	
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	N/A	N/A	N/A	33.4	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report (SPRA953).

5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	T_A = 25°C			SN54AHCT126		SN74AHCT126		SN74AHCT126 –40 to 125°C		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
V_{OH}	I_{OH} = –50 µA	4.5 V	4.4	4.5		4.4		4.4		4.4		V
	I_{OH} = –8 mA		3.94			3.8		3.8		3.8		
V_{OL}	I_{OL} = 50 µA	4.5 V			0.1		0.1		0.1		0.1	V
	I_{OL} = 8 mA				0.36		0.44		0.44		0.44	
I_I	V_I = 5.5 V or GND	0 V to 5.5 V			±0.1		±1[1]		±1		±1	µA
I_{OZ}	V_O = V_{CC} or GND	5.5 V			±0.25		±2.5		±2.5		±2.5	µA
I_{CC}	V_I = V_{CC} or GND I_O = 0	5.5 V			2		20		20		20	µA
ΔI_{CC} [2]	One input at 3.4 V, Other inputs at V_{CC} or GND	5.5 V			1.35		1.5		1.5		1.5	mA
C_i	V_I = V_{CC} or GND	5 V		4	10				10			pF
C_o	V_O = V_{CC} or GND	5 V		15								pF

(1) On products compliant to MIL-PRF-38535, this parameter is not production tested at V_{CC} = 0 V.
(2) This is the increase in supply current for each input at one of the specified TTL voltage levels, rather than 0 V or V_{CC}.

Copyright © 2024 Texas Instruments Incorporated

5.6 Switching Characteristics, V_{CC} = 5 V ± 0.5 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 6-1)

PARAMETER	FROM (OUTPUT)	TO (INPUT)	LOAD CAPACITANCE	T_A = 25°C			SN54AHCT126 –55°C to 125°C		SN74AHCT126 –40°C to 85°C		SN74AHCT126 –40°C to 125°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A	Y	C_L = 15 pF		3.8[1]	5.5[1]	1[1]	6.5[1]	1	6.5	1	7	ns
t_{PHL}					3.8[1]	5.5[1]	1[1]	6.5[1]	1	6.5	1	7	
t_{PZH}	OE	Y	C_L = 15 pF		3.6[1]	5.1[1]	1[1]	6[1]	1	6	1	6.5	ns
t_{PZL}					3.6[1]	5.1[1]	1[1]	6[1]	1	6	1	6.5	
t_{PHZ}	OE	Y	C_L = 15 pF		4.6[1]	6.8[1]	1[1]	8[1]	1	8	1	8.5	ns
t_{PLZ}					4.6[1]	6.8[1]	1[1]	8[1]	1	8	1	8.5	
t_{PLH}	A	Y	C_L = 50 pF		5.3	7.5	1	8.5	1	8.5	1	9.5	ns
t_{PHL}					5.3	7.5	1	8.5	1	8.5	1	9.5	
t_{PZH}	OE	Y	C_L = 50 pF		5.1	7.1	1	8	1	8	1	9	ns
t_{PZL}					5.1	7.1	1	8	1	8	1	9	
t_{PHZ}	OE	Y	C_L = 50 pF		6.1	8.8	1	10	1	10	1	11	ns
t_{PLZ}					6.1	8.8	1	10	1	10	1	11	
$t_{sk(o)}$			C_L = 50 pF			1[2]				1		1	ns

(1) On products compliant to MIL-PRF-38535, this parameter is not production tested.
(2) On products compliant to MIL-PRF-38535, this parameter does not apply.

5.7 Noise Characteristics

V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C[1]

PARAMETER		SN74AHCT126		UNIT
		MIN	MAX	
$V_{OL(P)}$	Quiet output, maximum dynamic V_{OL}		0.8	V
$V_{OL(V)}$	Quiet output, minimum dynamic V_{OL}		–0.8	V
$V_{OH(V)}$	Quiet output, minimum dynamic V_{OH}	4.4		V
$V_{IH(D)}$	High-level dynamic input voltage	2		V
$V_{IL(D)}$	Low-level dynamic input voltage		0.8	V

(1) Characteristics are for surface-mount packages only.

5.8 Operating Characteristics

V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS		TYP	UNIT
C_{pd}	Power dissipation capacitance	No load,	f = 1 MHz	14	pF

Copyright © 2024 Texas Instruments Incorporated

5.9 Typical Characteristics

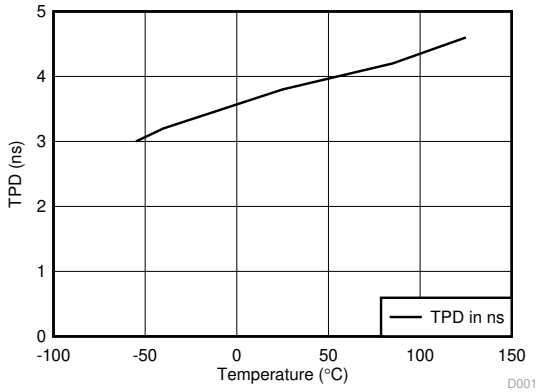
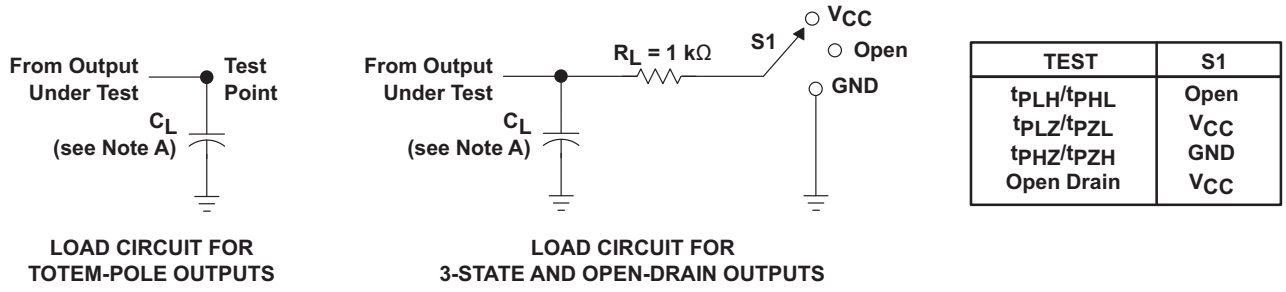


Figure 5-1. TPD vs Temperature

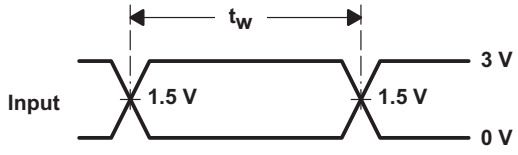
Copyright © 2024 Texas Instruments Incorporated

6 Parameter Measurement Information

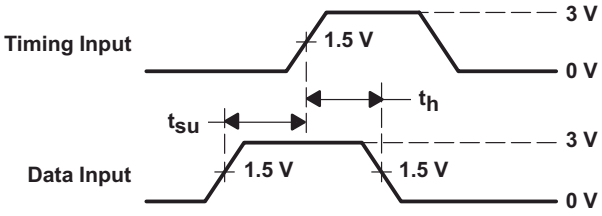


LOAD CIRCUIT FOR TOTEM-POLE OUTPUTS

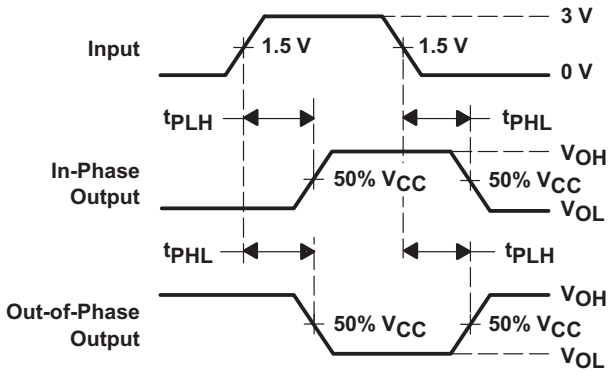
LOAD CIRCUIT FOR 3-STATE AND OPEN-DRAIN OUTPUTS



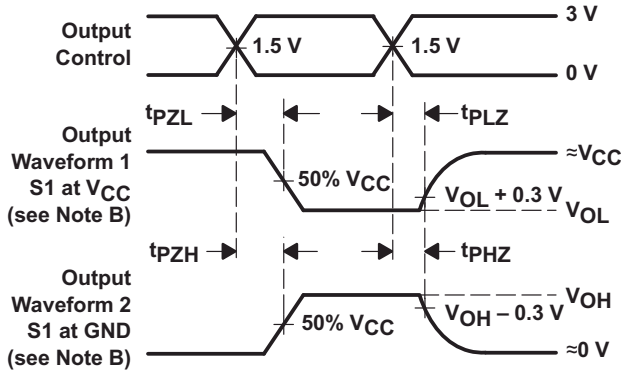
VOLTAGE WAVEFORMS PULSE DURATION



VOLTAGE WAVEFORMS SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES LOW- AND HIGH-LEVEL ENABLING

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r ≤ 3 ns, t_f ≤ 3 ns.
D. The outputs are measured one at a time with one input transition per measurement.
E. All parameters and waveforms are not applicable to all devices.

Figure 6-1. Load Circuit and Voltage and Waveforms

Copyright © 2024 Texas Instruments Incorporated

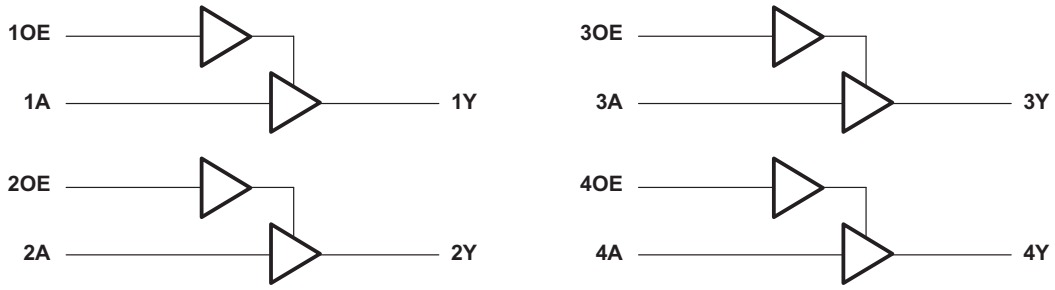
7 Detailed Description

7.1 Overview

The SNxAHCT126 devices are quadruple-bus buffer gates featuring independent line drivers with 3-state outputs.

Each output is disabled when the associated output-enable (OE) input is low. When OE is high, the respective gate passes the data from the A input to the Y output. For the high-impedance state during power up or power down, tie OE to GND through a pull-down resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

7.2 Functional Block Diagram



7.3 Feature Description

- TTL inputs
  - Lowered switching threshold allows up translation from 3.3 V to 5 V
- Slow edges reduce output ringing

7.4 Device Functional Modes

Table 7-1. Function Table (Each Buffer)

INPUTS		OUTPUT Y
OE	A	
H	H	H
H	L	L
L	X	Z

Copyright © 2024 Texas Instruments Incorporated

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The SNx4AHCT126 is a low-drive CMOS device that can be used for a multitude of bus interface type applications where output ringing is a concern. The low drive and slow edge rates will minimize overshoot and undershoot on the outputs. The input switching levels have been lowered to accommodate TTL inputs of 0.8-V V_{IL} and 2-V V_{IH}. This feature makes it ideal for translating up from 3.3 V to 5 V. Figure 8-2 shows this type of translation.

8.2 Typical Application

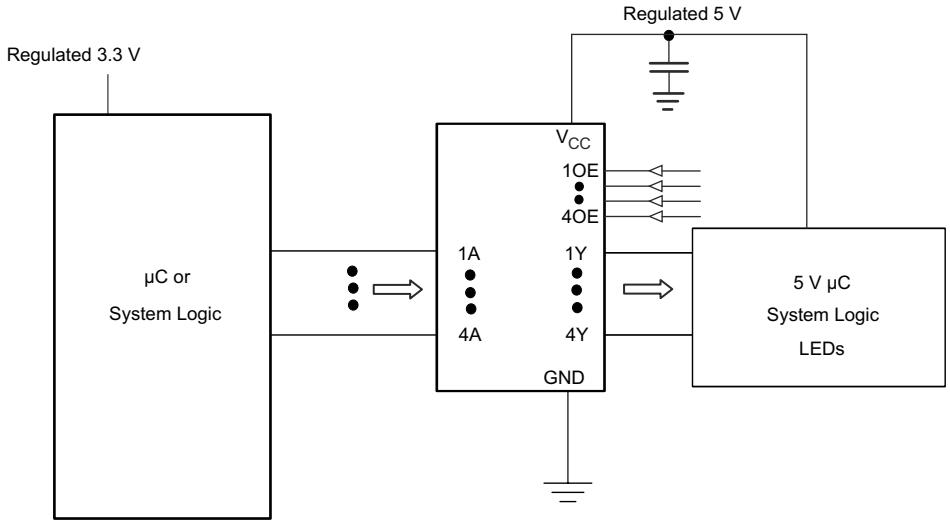


Figure 8-1. Typical Application Schematic

8.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Care should be taken to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads; therefore, routing and load conditions should be considered to prevent ringing.

8.2.2 Detailed Design Procedure

1. Recommended input conditions:
   - Rise time and fall time specs: See (Δt/ΔV) in the *Recommended Operating Conditions* table.
   - Specified High and low levels: See (V_{IH} and V_{IL}) in the *Recommended Operating Conditions* table.
   - Inputs are overvoltage tolerant allowing them to go as high as 5.5 V at any valid V_{CC}
2. Recommended output conditions:
   - Load currents should not exceed 25 mA per output and 50 mA total for the part
   - Outputs should not be pulled above V_{CC}

Copyright © 2024 Texas Instruments Incorporated

8.2.3 Application Curves

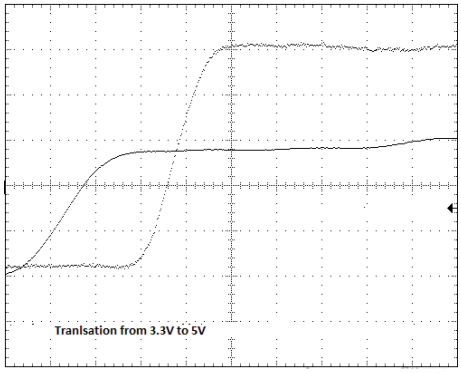


Figure 8-2. Up Translation

8.3 Power Supply Recommendations

The power supply can be any voltage between the MIN and MAX supply voltage rating located in the *Recommended Operating Conditions* table.

Each V_{CC} pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, 0.1 µF is recommended. If there are multiple V_{CC} pins, 0.01 µF or 0.022 µF is recommended for each power pin. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. A 0.1 µF and 1 µF are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

8.4 Layout

8.4.1 Layout Guidelines

When using multiple bit logic devices inputs should not ever float.

In many cases, functions or parts of functions of digital logic devices are unused, for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. Figure 8-3 shows the rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or V_{CC}; whichever makes more sense or is more convenient. It is generally acceptable to float outputs unless the part is a transceiver. If the transceiver has an output enable pin, it will disable the outputs section of the part when asserted. This will not disable the input section of the IO's so they cannot float when disabled.

8.4.2 Layout Example

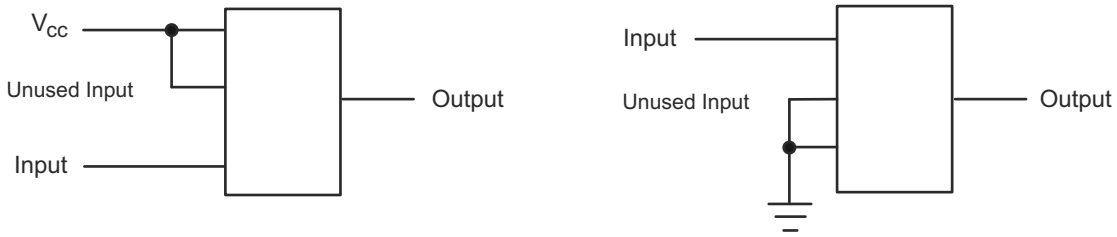


Figure 8-3. Layout Diagram

Copyright © 2024 Texas Instruments Incorporated

9 Device and Documentation Support

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.
All trademarks are the property of their respective owners.

9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

TI Glossary	This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision R (October 2023) to Revision S (February 2024)	Page
• Updated thermal values for NS package from RθJA = 90.7 to 120.9, RθJC(top) = 48.3 to 78.2, RθJB = 49.4 to 81.6, ΨJT = 14.6 to 42.8, ΨJB = 49.1 to 81.1, RθJC(bot) = N/A, all values in °C/W	6

Changes from Revision Q (May 2023) to Revision R (October 2023)	Page
• Updated RθJA values: D = 90.6 to 124.5, PW = 122.6 to 147.7; Updated D and PW packages for RθJC(top), RθJB, ΨJT, ΨJB, and RθJC(bot), all values in °C/W	6

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Copyright © 2024 Texas Instruments Incorporated

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
5962-9686301QDA	NRND	Production	CFP (W) | 14	25 | TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-9686301QD A SNJ54AHCT126W
SN74AHCT126BQAR	Active	Production	WQFN (BQA) | 14	3000 | LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	AHT126
SN74AHCT126BQAR.A	Active	Production	WQFN (BQA) | 14	3000 | LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	AHT126
SN74AHCT126D	Obsolete	Production	SOIC (D) | 14	-	-	Call TI	Call TI	-40 to 85	AHCT126
SN74AHCT126DBR	Active	Production	SSOP (DB) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB126
SN74AHCT126DBR.A	Active	Production	SSOP (DB) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB126
SN74AHCT126DGVR	Active	Production	TVSOP (DGV) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB126
SN74AHCT126DGVR.A	Active	Production	TVSOP (DGV) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB126
SN74AHCT126DR	Active	Production	SOIC (D) | 14	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT126
SN74AHCT126DR.A	Active	Production	SOIC (D) | 14	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT126
SN74AHCT126N	Active	Production	PDIP (N) | 14	25 | TUBE	Yes	NIPDAU	N/A for Pkg Type	-40 to 125	SN74AHCT126N
SN74AHCT126N.A	Active	Production	PDIP (N) | 14	25 | TUBE	Yes	NIPDAU	N/A for Pkg Type	-40 to 125	SN74AHCT126N
SN74AHCT126NSR	Active	Production	SOP (NS) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT126
SN74AHCT126NSR.A	Active	Production	SOP (NS) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT126
SN74AHCT126PW	Obsolete	Production	TSSOP (PW) | 14	-	-	Call TI	Call TI	-40 to 125	HB126
SN74AHCT126PWR	Active	Production	TSSOP (PW) | 14	2000 | LARGE T&R	Yes	NIPDAU | SN	Level-1-260C-UNLIM	-40 to 125	HB126
SN74AHCT126PWR.A	Active	Production	TSSOP (PW) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB126
SNJ54AHCT126W	NRND	Production	CFP (W) | 14	25 | TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-9686301QD A SNJ54AHCT126W
SNJ54AHCT126W.A	NRND	Production	CFP (W) | 14	25 | TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-9686301QD A SNJ54AHCT126W

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN54AHCT126, SN74AHCT126 :

- Catalog : SN74AHCT126
- Automotive : SN74AHCT126-Q1, SN74AHCT126-Q1
- Enhanced Product : SN74AHCT126-EP, SN74AHCT126-EP
- Military : SN54AHCT126

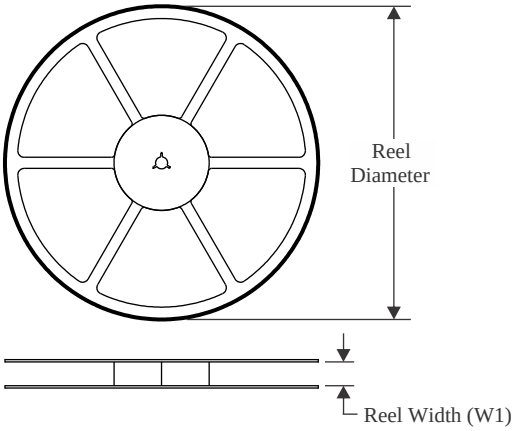
NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Enhanced Product - Supports Defense, Aerospace and Medical Applications

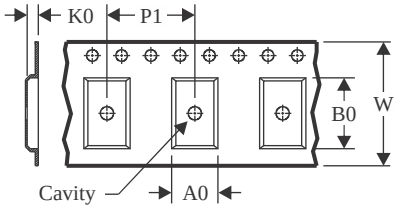
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION

REEL DIMENSIONS

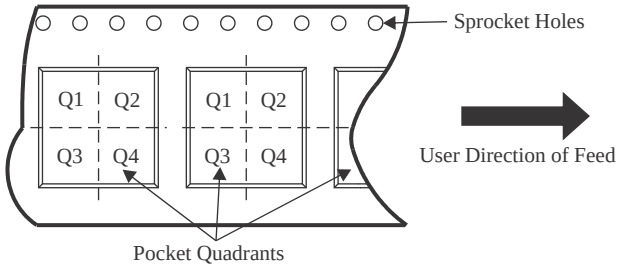


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

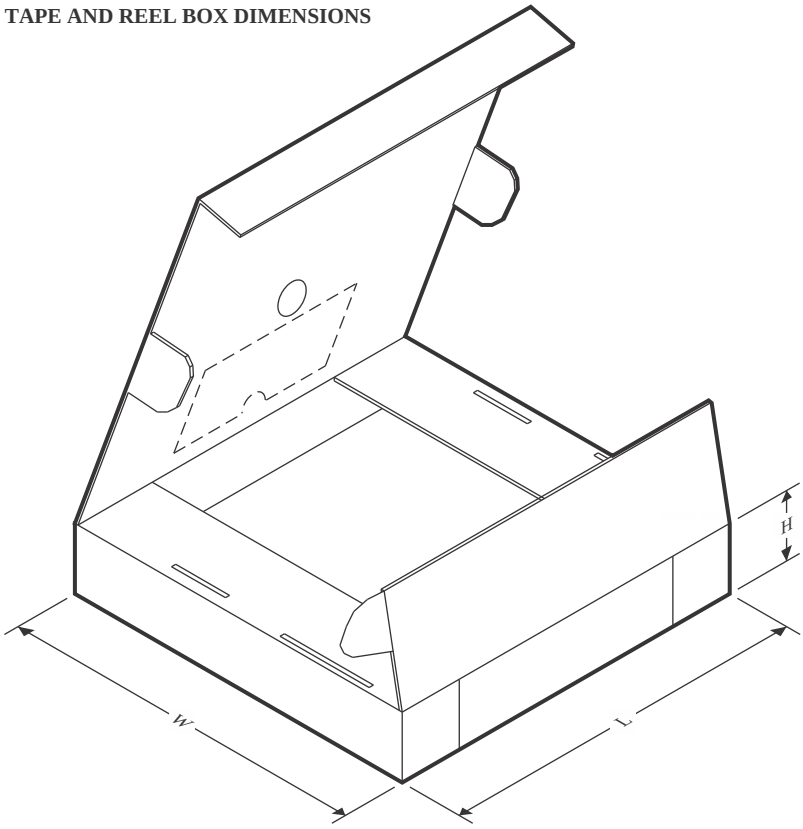
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHCT126BQAR	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1
SN74AHCT126DBR	SSOP	DB	14	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
SN74AHCT126DGVR	TVSOP	DGV	14	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
SN74AHCT126DR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
SN74AHCT126NSR	SOP	NS	14	2000	330.0	16.4	8.1	10.4	2.5	12.0	16.0	Q1
SN74AHCT126NSR	SOP	NS	14	2000	330.0	16.4	8.45	10.55	2.5	12.0	16.2	Q1
SN74AHCT126PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT126PWR	TSSOP	PW	14	2000	330.0	12.4	6.85	5.45	1.6	8.0	12.0	Q1

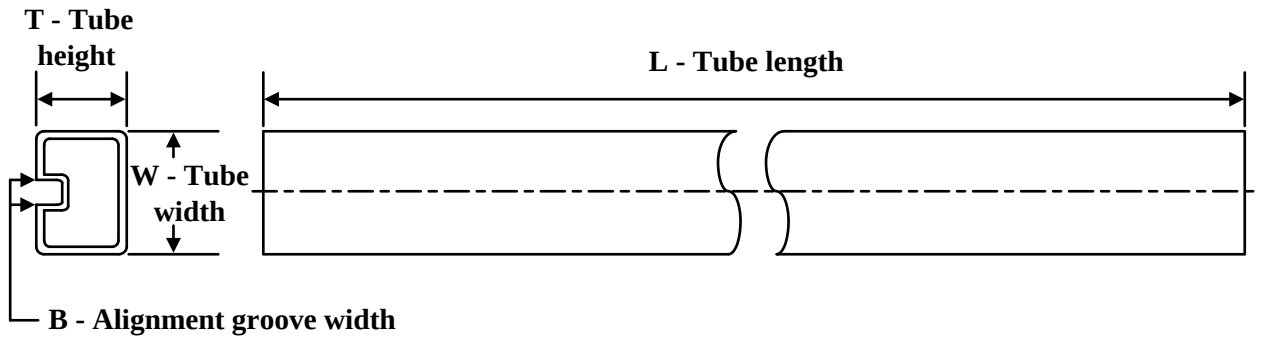
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

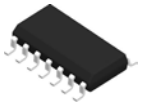
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHCT126BQAR	WQFN	BQA	14	3000	210.0	185.0	35.0
SN74AHCT126DBR	SSOP	DB	14	2000	353.0	353.0	32.0
SN74AHCT126DGVR	TVSOP	DGV	14	2000	353.0	353.0	32.0
SN74AHCT126DR	SOIC	D	14	2500	353.0	353.0	32.0
SN74AHCT126NSR	SOP	NS	14	2000	353.0	353.0	32.0
SN74AHCT126NSR	SOP	NS	14	2000	353.0	353.0	32.0
SN74AHCT126PWR	TSSOP	PW	14	2000	353.0	353.0	32.0
SN74AHCT126PWR	TSSOP	PW	14	2000	366.0	364.0	50.0

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
5962-9686301QDA	W	CFP	14	25	506.98	26.16	6220	NA
SN74AHCT126N	N	PDIP	14	25	506	13.97	11230	4.32
SN74AHCT126N	N	PDIP	14	25	506	13.97	11230	4.32
SN74AHCT126N.A	N	PDIP	14	25	506	13.97	11230	4.32
SN74AHCT126N.A	N	PDIP	14	25	506	13.97	11230	4.32
SNJ54AHCT126W	W	CFP	14	25	506.98	26.16	6220	NA
SNJ54AHCT126W.A	W	CFP	14	25	506.98	26.16	6220	NA

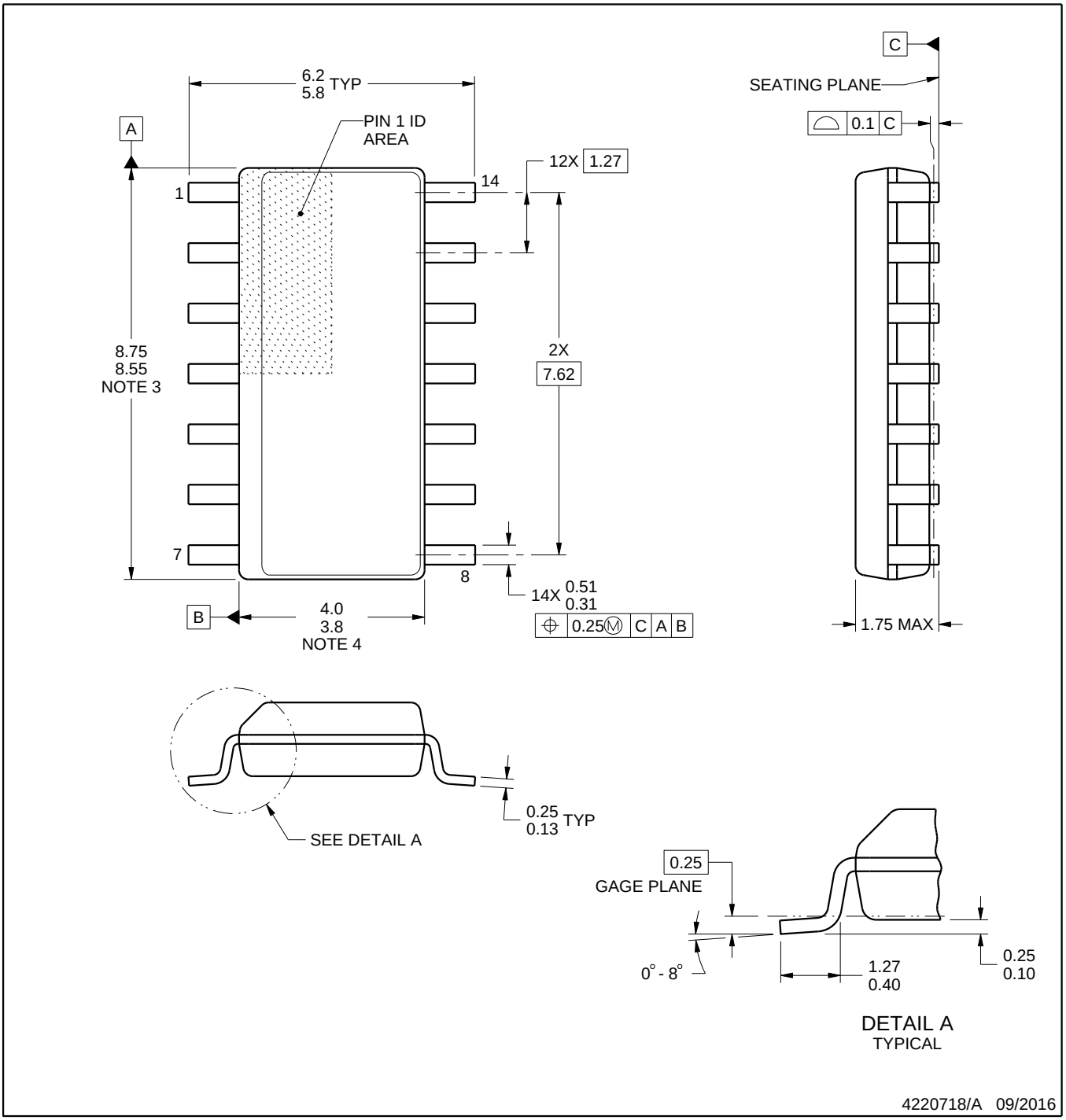


PACKAGE OUTLINE

D0014A

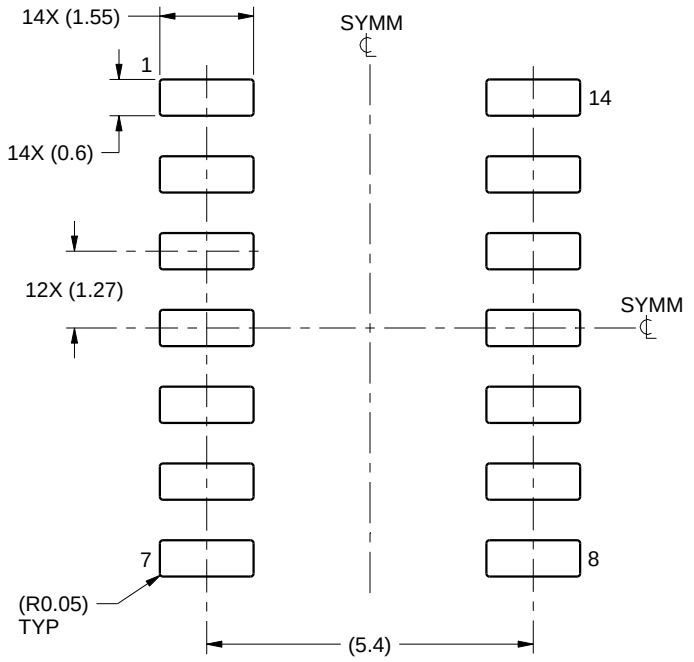
SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

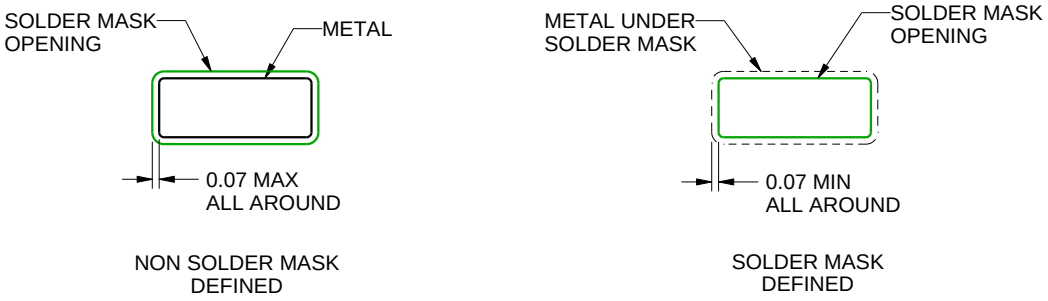


NOTES:

1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
5. Reference JEDEC registration MS-012, variation AB.



LAND PATTERN EXAMPLE
SCALE:8X



SOLDER MASK DETAILS

4220718/A 09/2016

NOTES: (continued)

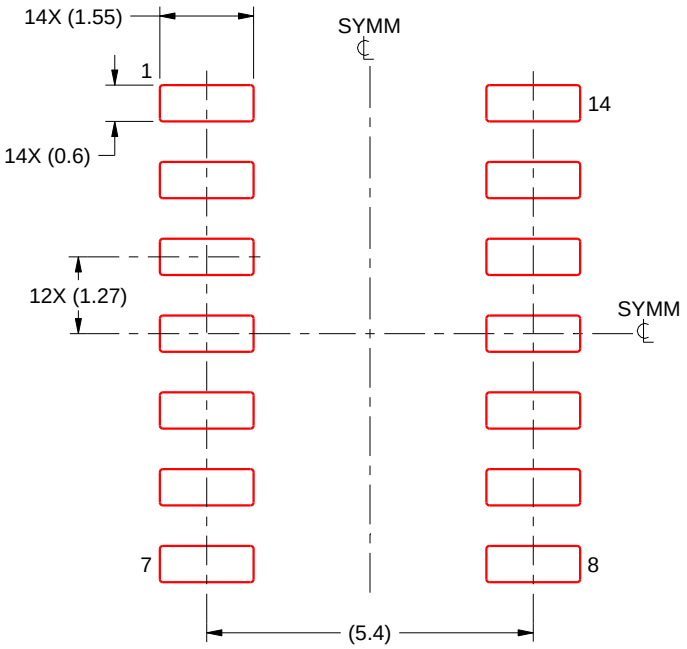
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0014A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:8X

4220718/A 09/2016

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

GENERIC PACKAGE VIEW

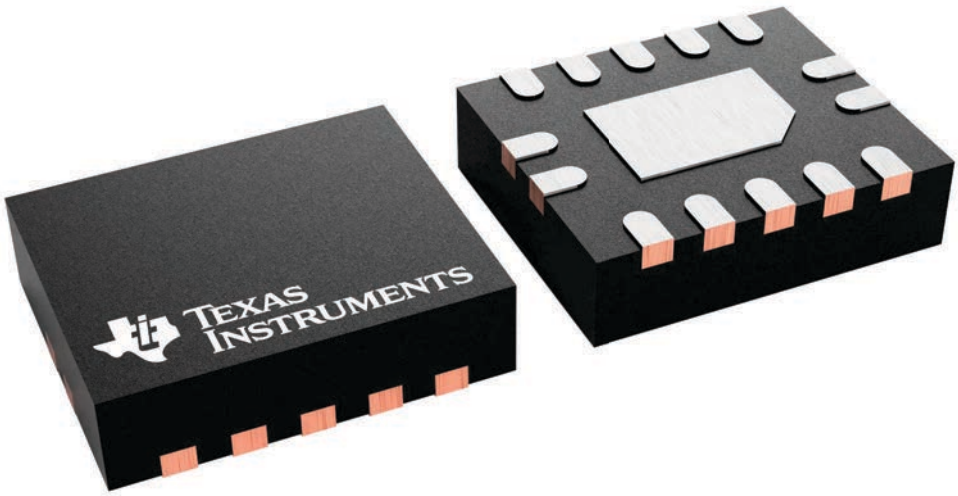
BQA 14

WQFN - 0.8 mm max height

2.5 x 3, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.

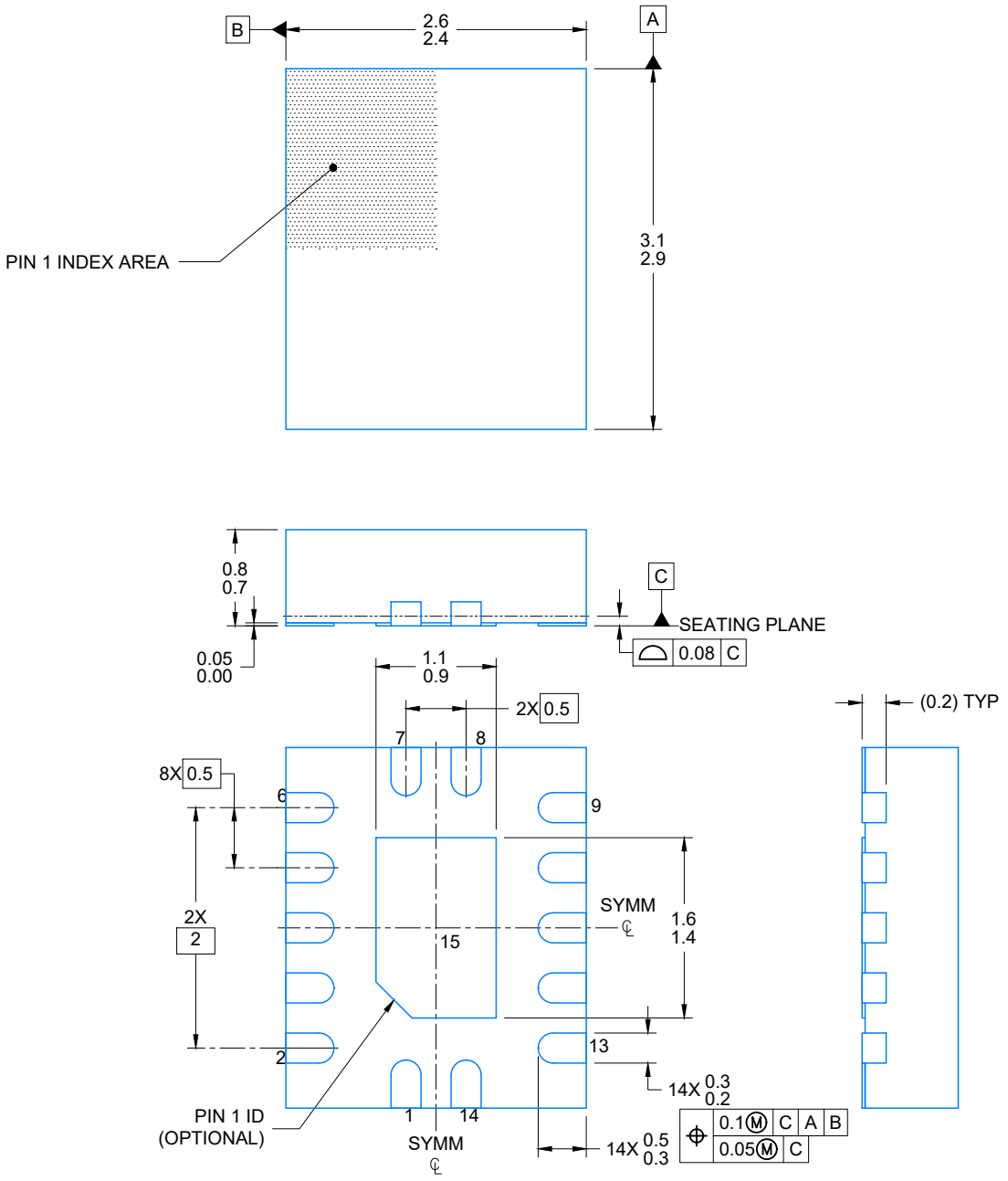


PACKAGE OUTLINE

BQA0014A

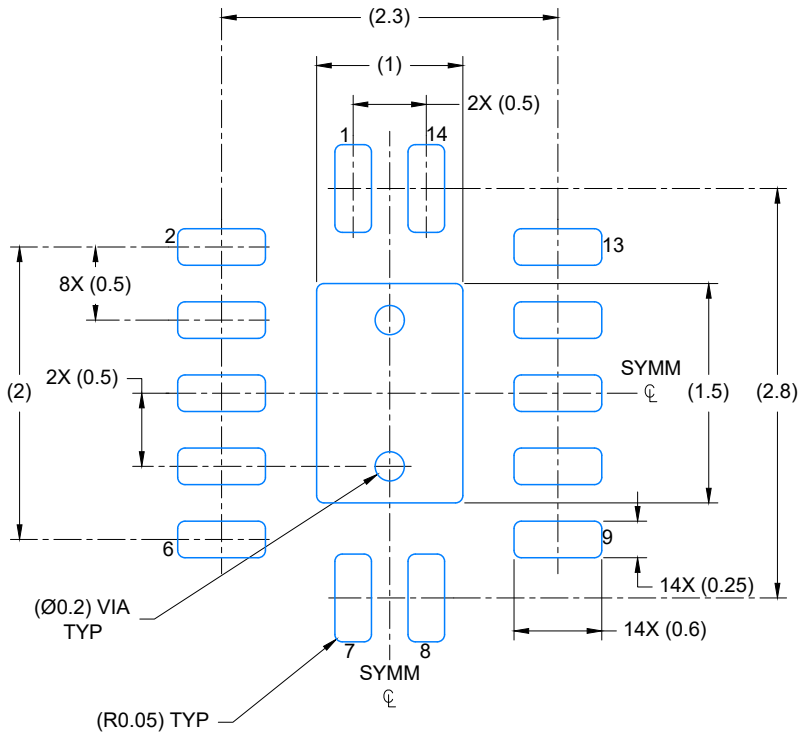
WQFN - 0.8 mm max height

PLASTIC QUAD FLAT PACK-NO LEAD

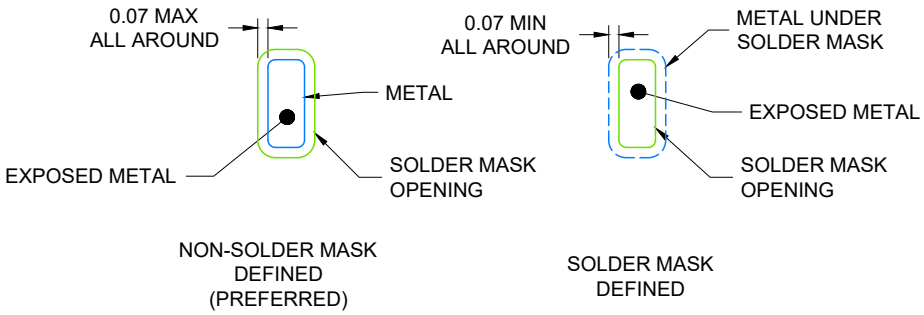


NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



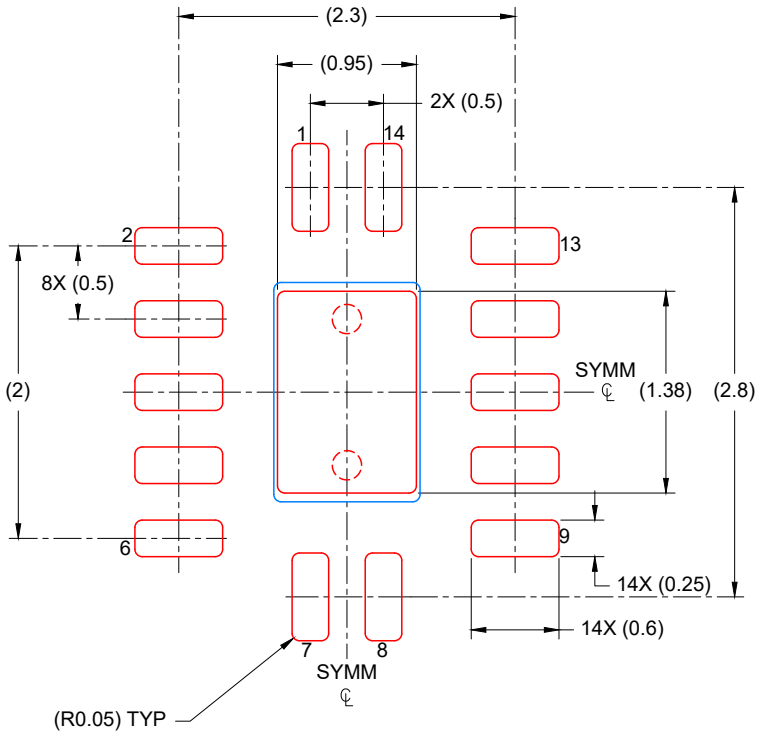
LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 20X



4224636/A 11/2018

NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL

EXPOSED PAD
88% PRINTED COVERAGE BY AREA
SCALE: 20X

4224636/A 11/2018

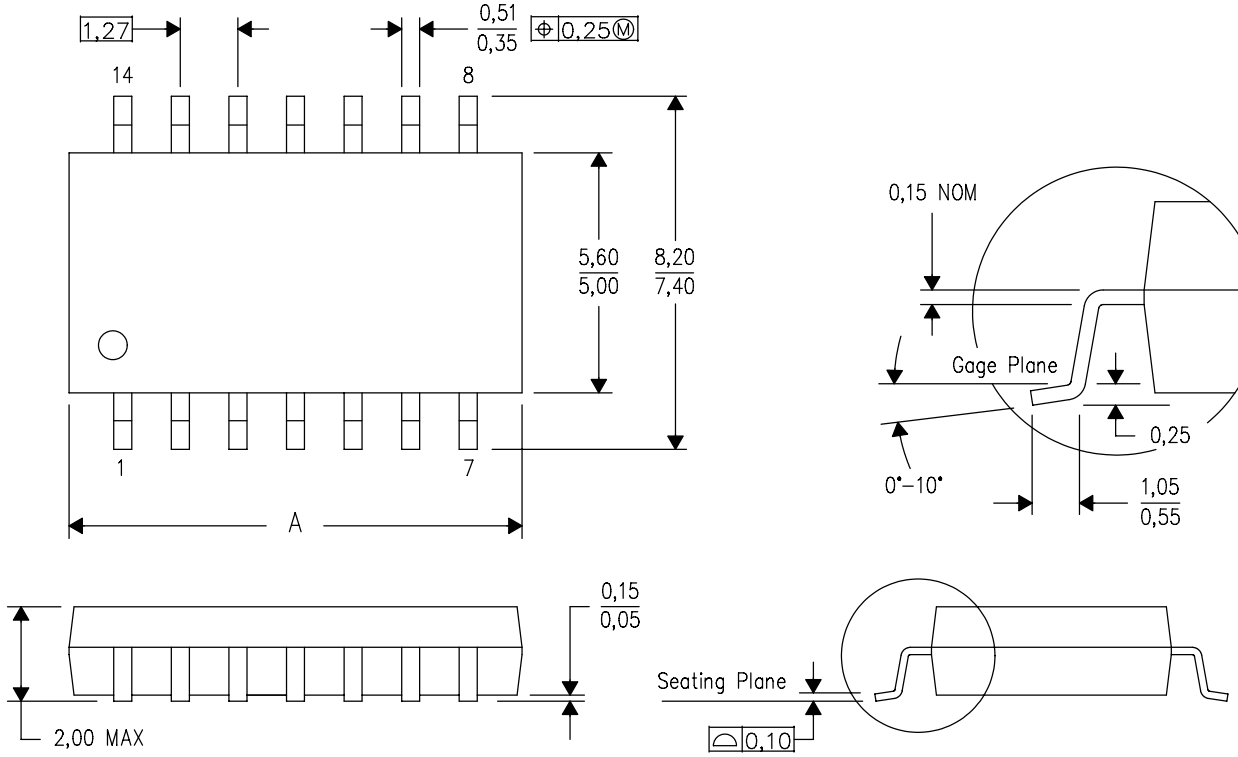
NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

MECHANICAL DATA

NS (R-PDSO-G)** **PLASTIC SMALL-OUTLINE PACKAGE**

14-PINS SHOWN

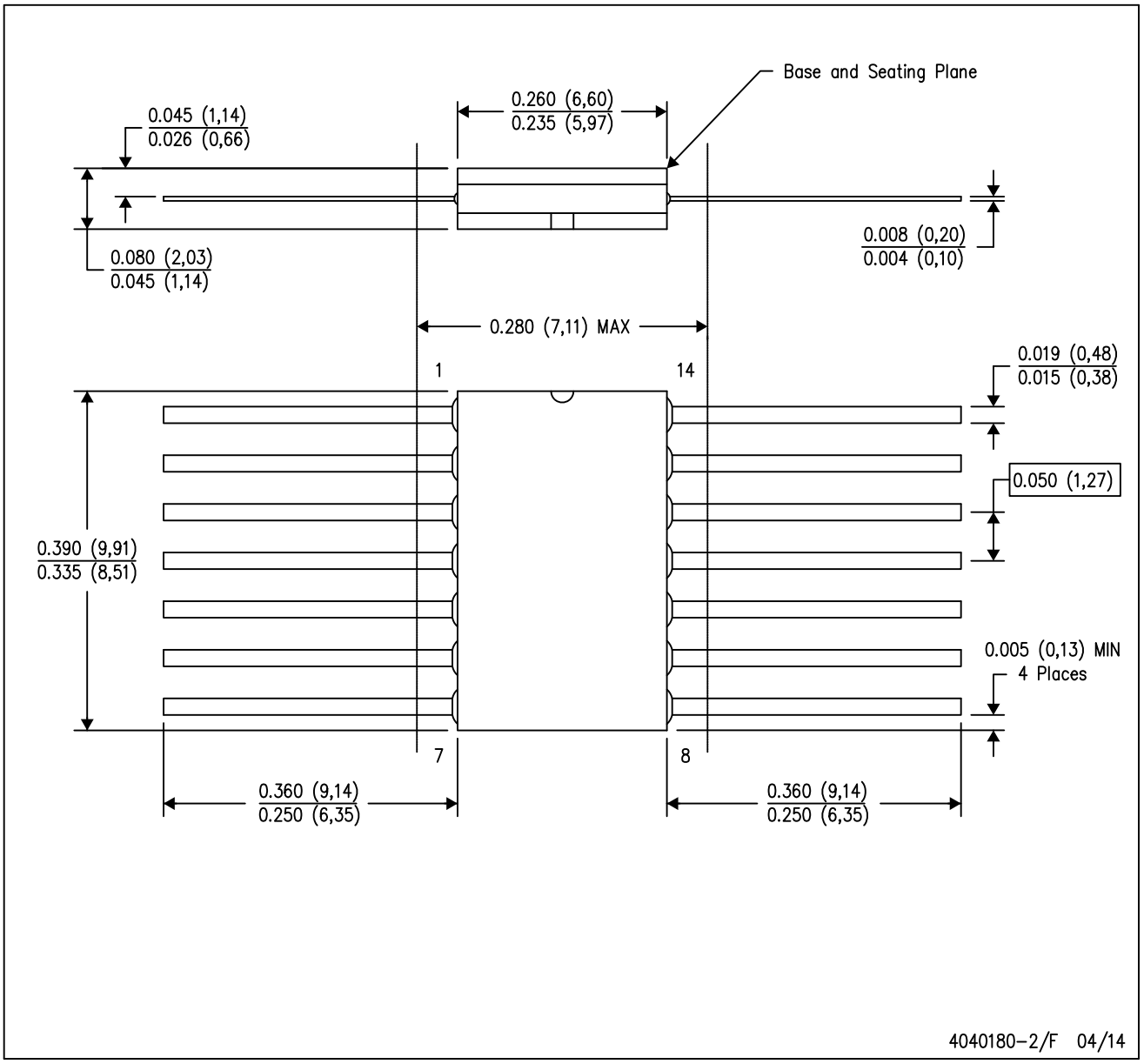


DIM \ PINS **	14	16	20	24
A MAX	10,50	10,50	12,90	15,30
A MIN	9,90	9,90	12,30	14,70

4040062/C 03/03

NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.

W (R–GDFP–F14) CERAMIC DUAL FLATPACK



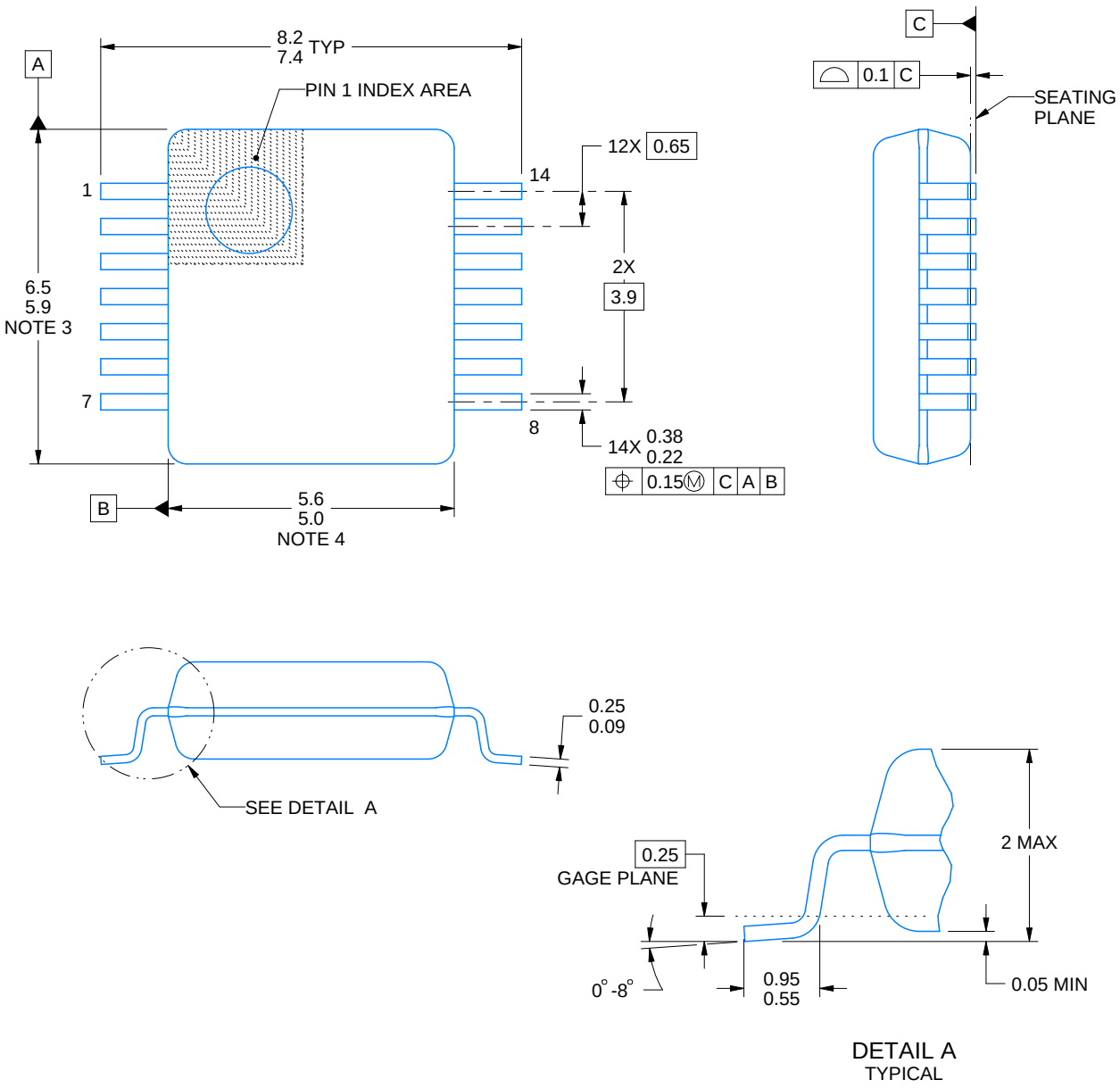
NOTES:
A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. This package can be hermetically sealed with a ceramic lid using glass frit.
D. Index point is provided on cap for terminal identification only.
E. Falls within MIL STD 1835 GDFP1–F14

PACKAGE OUTLINE

DB0014A

SSOP - 2 mm max height

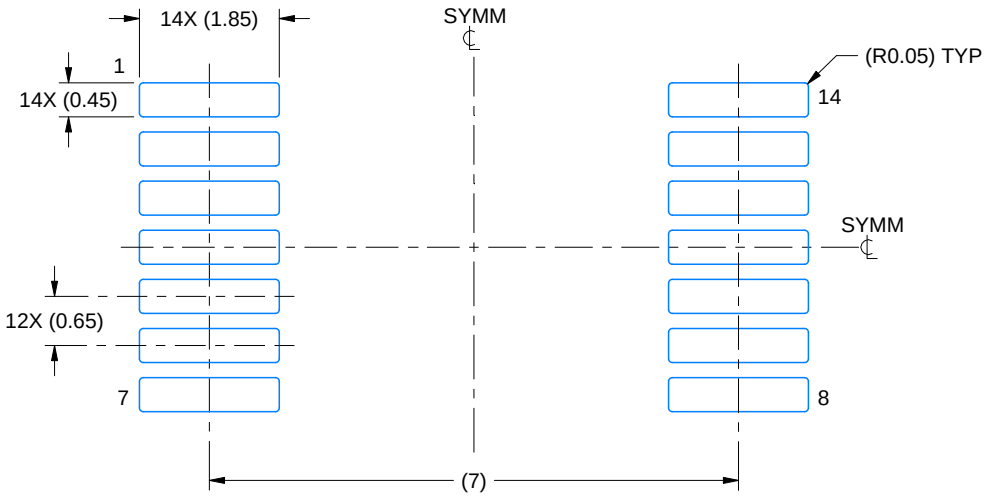
SMALL OUTLINE PACKAGE



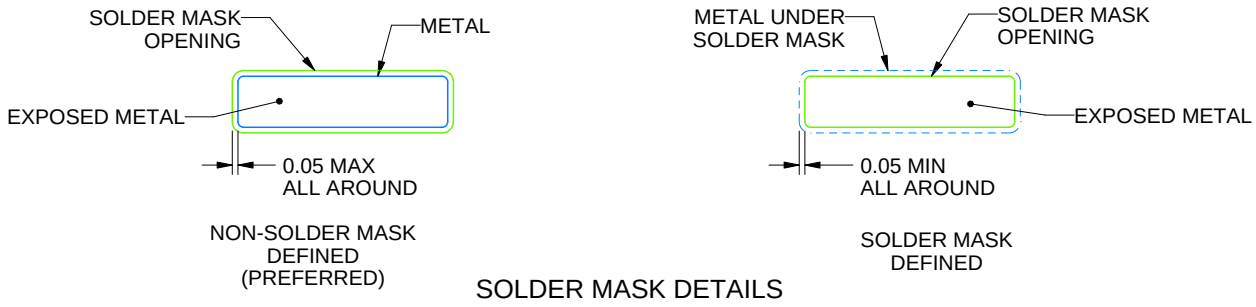
4220762/A 05/2024

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. Reference JEDEC registration MO-150.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X

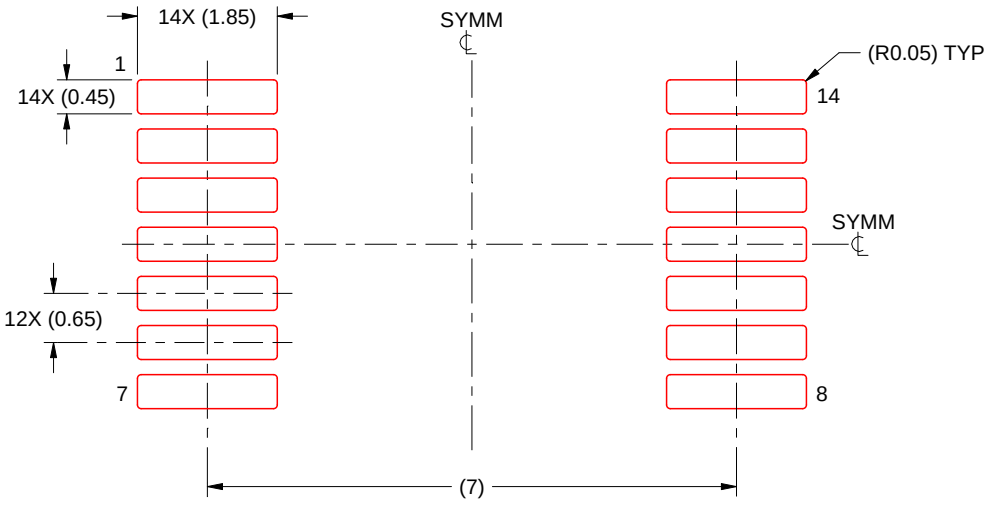


SOLDER MASK DETAILS

4220762/A 05/2024

NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.
6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220762/A 05/2024

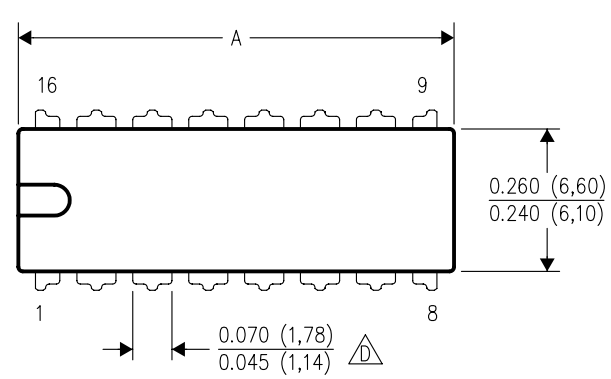
NOTES: (continued)

7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
8. Board assembly site may have different recommendations for stencil design.

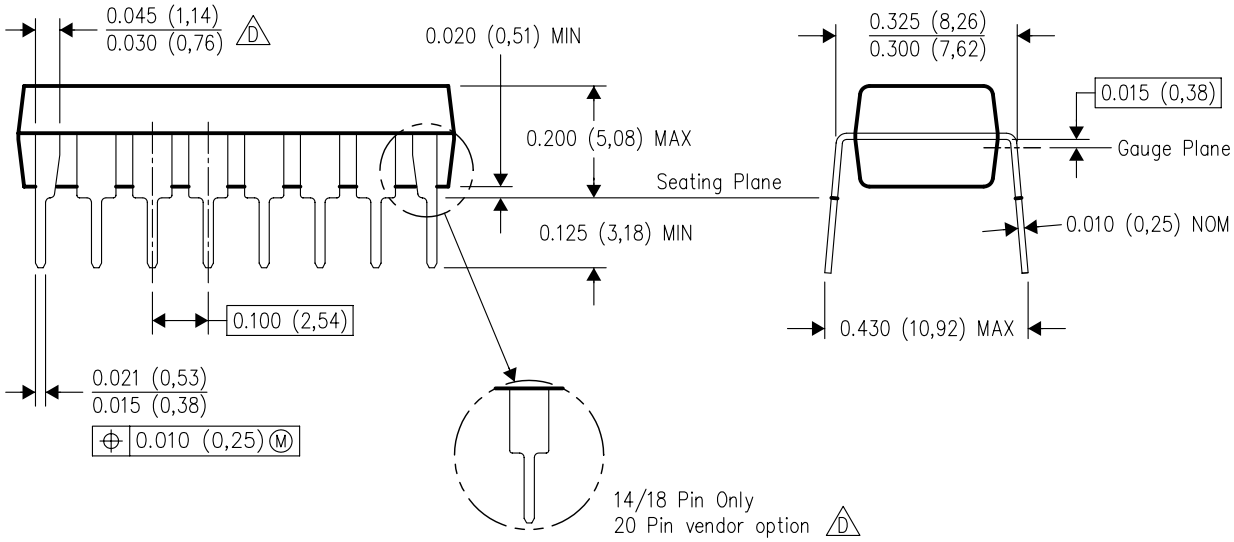
N (R–PDIP–T**)

PLASTIC DUAL–IN–LINE PACKAGE

16 PINS SHOWN



DIM \ PINS **	14	16	18	20
A MAX	0.775 (19,69)	0.775 (19,69)	0.920 (23,37)	1.060 (26,92)
A MIN	0.745 (18,92)	0.745 (18,92)	0.850 (21,59)	0.940 (23,88)
MS–001 VARIATION (C)	AA	BB	AC	AD



4040049/E 12/2002

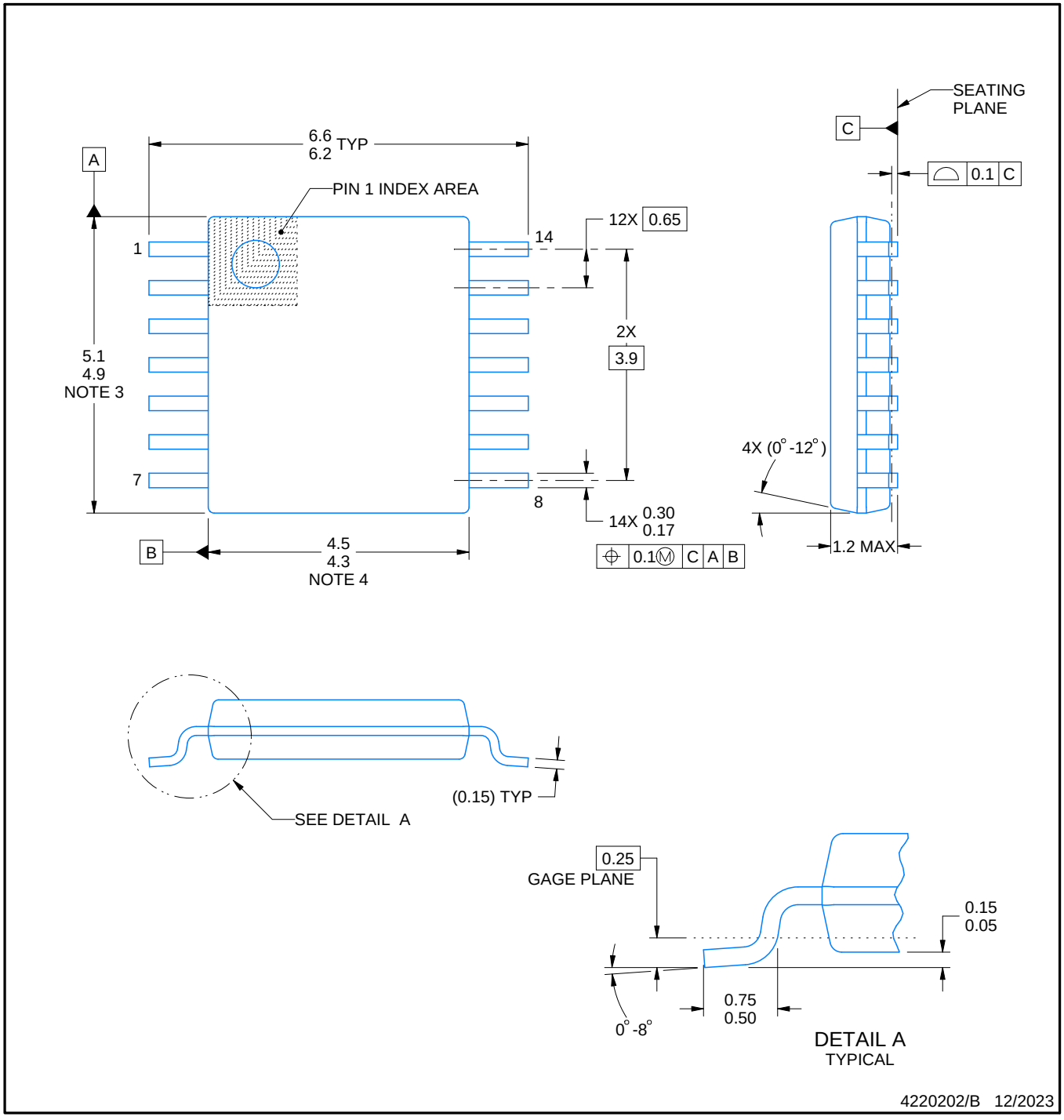
NOTES:
A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Falls within JEDEC MS–001, except 18 and 20 pin minimum body length (Dim A).
D. The 20 pin end lead shoulder width is a vendor option, either half or full width.

PACKAGE OUTLINE

PW0014A

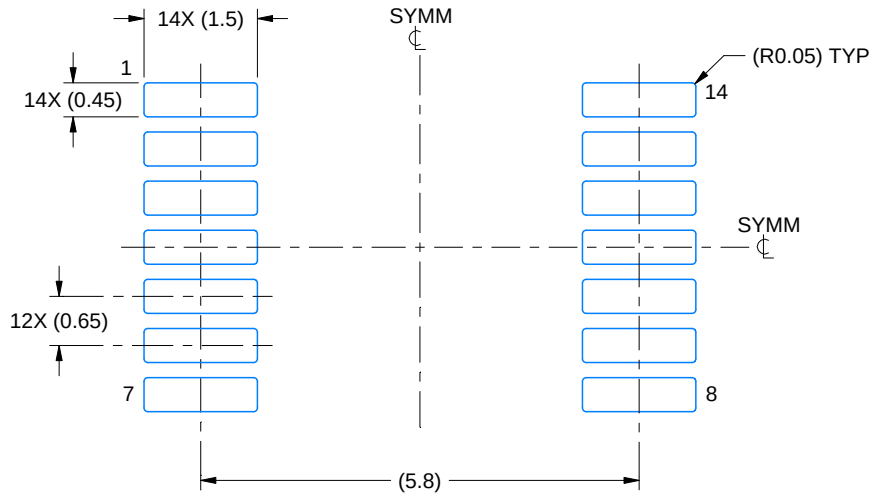
TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE

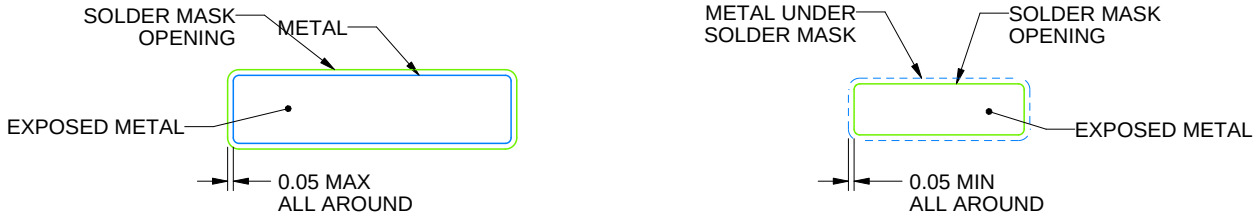


NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X

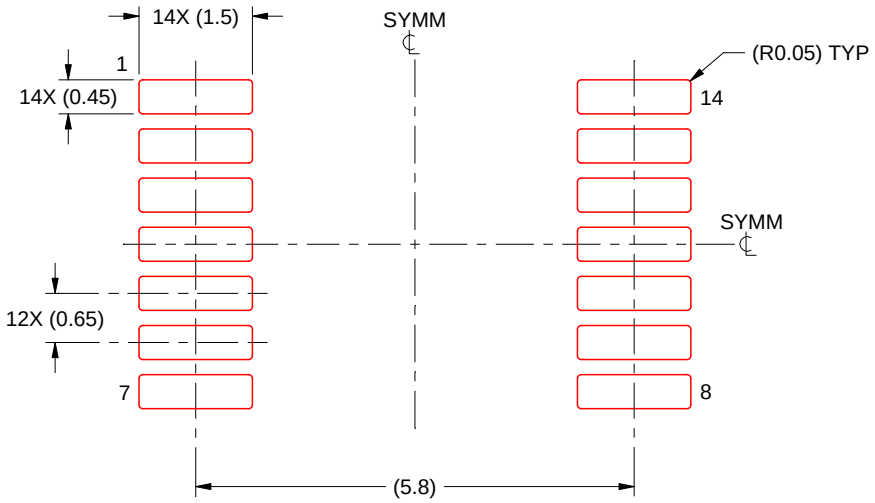


SOLDER MASK DETAILS

4220202/B 12/2023

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220202/B 12/2023

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES “AS IS” AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI’s products are provided subject to TI’s Terms of Sale, TI’s General Quality Guidelines, or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI’s provision of these resources does not expand or otherwise alter TI’s applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2026, Texas Instruments Incorporated

Last updated 10/2025